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Nadeau-Dostie et al.

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(54) **MEMORY REPAIR CIRCUIT AND METHOD**

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(58) **Field of Classification Search** 714/8,
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See application file for complete search history.

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(57) **ABSTRACT**

A self-repair circuit for a semiconductor memory provides input and output test selectors coupled to respective data bit group inputs and outputs, respectively and input and output repair selectors coupled between the input and output test selectors and functional inputs and functional outputs, respectively. This arrangement allows all data bit groups to be tested in one pass and all test and repair selector circuitry to be tested.

18 Claims, 5 Drawing Sheets

